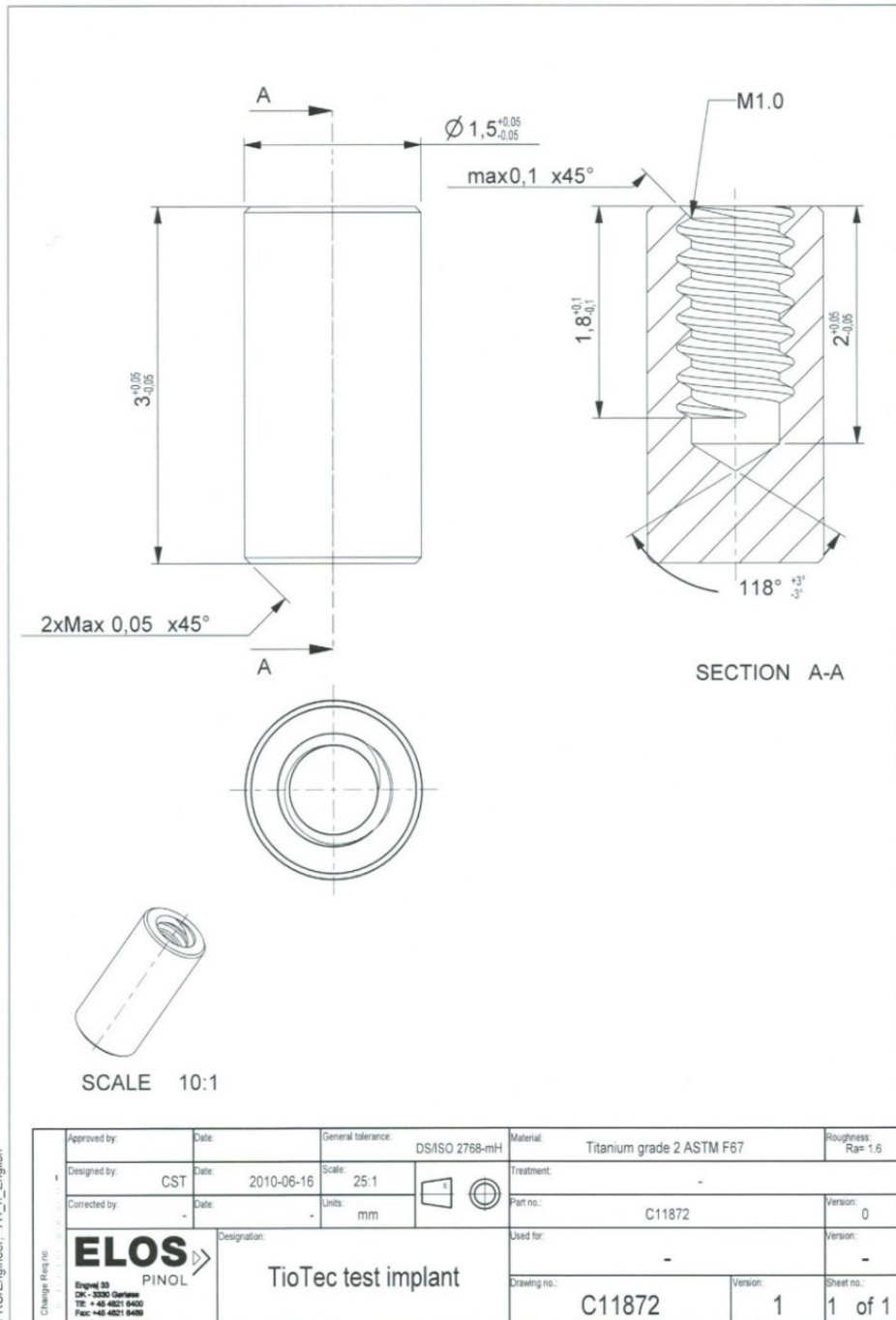


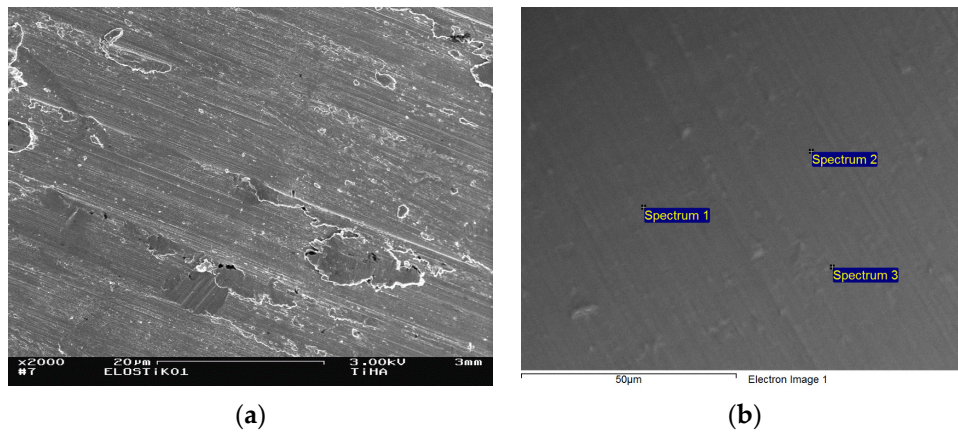
# Supplementary Materials

Characterisation of implants manufacturing (Figure S1).



**Figure S1.** Titanium implant (commercially available).

Scanning electron microscopy of a Ti-implant taken directly from the manufacturers package. Marks of the milling tool can be seen in the micrometer range (Figure S2).



**Figure S2.** (a) ESEM image and (b) EDX analysis of the c.p. Ti-implant.

The EDX data (Table S1) indicate contamination with a carbon layer.

**Table S1.** Atomic species analysed with EDX.

Ti, c.p.	C	O	Ti
Spectrum 1	28.87	8.76	62.22
Spectrum 2	29.10	9.28	61.42
Spectrum 3	26.56	–	73.26



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